

<b>Notice of References Cited</b>	Application/Control No. 10/763,078		Applicant(s)/Patent Under Reexamination NAICK ET AL.	
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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-7,280,530	10-2007	Chang et al.	370/352
*	B	US-7,251,234	07-2007	Warmus et al.	370/338
*	C	US-7,206,304	04-2007	Low et al.	370/352
*	D	US-7,155,425	12-2006	Nykanen, Petri	707/3
*	E	US-7,058,726	06-2006	Osaku et al.	709/245
*	F	US-6,999,444	02-2006	Nitta et al.	370/338
*	G	US-6,963,928	11-2005	Bagley et al.	709/245
*	H	US-6,859,451	02-2005	Pasternack et al.	370/352
*	I	US-6,842,612	01-2005	Kalish et al.	455/414.2
*	J	US-6,865,608	03-2005	Hunter, Kevin D.	709/229
*	K	US-6,788,769	09-2004	Waites, Nigel	379/93.24
*	L	US-6,628,644	09-2003	Nelson et al.	370/352
*	M	US-2002/0016174	02-2002	Gibson et al.	455/464

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

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